

### 20N40H TO3P-VB Datasheet

### N-Channel 500-V (D-S) Super Junction MOSFET

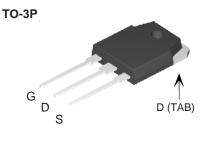
PRODUCT SUMMARY				
V <sub>DS</sub> (V) at T <sub>J</sub> max.	500			
R <sub>DS(on)</sub> at 25 °C (Ω)	$V_{GS} = 10 V$	0.192		
Q <sub>g</sub> max. (nC)	86			
Q <sub>gs</sub> (nC)	9			
Q <sub>gd</sub> (nC)	16			
Configuration	Single			

#### FEATURES

- Low figure-of-merit (FOM) Ron x Qg
- Low input capacitance (Ciss)
- Reduced switching and conduction losses
- Low gate charge (Q<sub>g</sub>)
- Avalanche energy rated (UIS)

#### **APPLICATIONS**

- Computing
  - PC silver box / ATX power supplies



N-Channel MOSFET

<b>ABSOLUTE MAXIMUM RATINGS</b> ( $T_C = 25 \text{ °C}$ , unless otherwise noted)							
PARAMETER	SYMBOL	LIMIT	UNIT				
Drain-Source Voltage	V <sub>DS</sub>	500	v				
Gate-Source Voltage	V <sub>GS</sub>	± 30					
Continuous Drain Current (T <sub>J</sub> = 150 °C)	$V_{GS}$ at 10 V $\frac{T_{C} = 25 \text{ °C}}{T_{C} = 100 \text{ °C}}$	- I <sub>D</sub>	18				
	$T_{\rm C} = 100 ^{\circ}{\rm C}$		12	А			
Pulsed Drain Current <sup>a</sup>		I <sub>DM</sub>	50				
Linear Derating Factor		1.25	W/°C				
Single Pulse Avalanche Energy <sup>b</sup>	E <sub>AS</sub>	186	mJ				
Maximum Power Dissipation	PD	206	W				
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	-55 to +150	°C			
Drain-Source Voltage Slope	$V_{DS} = 0 V$ to 80 % $V_{DS}$	dV/dt	70	1//20			
Reverse Diode dV/dt <sup>d</sup>	rse Diode dV/dt <sup>d</sup>		27	V/ns			
Soldering Recommendations (Peak Temperature) <sup>c</sup>	for 10 s		300	°C			

G

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature.

b.  $V_{DD}$  = 50 V, starting T<sub>J</sub> = 25 °C, L = 28.2 mH, R<sub>g</sub> = 25  $\Omega$ , I<sub>AS</sub> = 3.1 A.

c. 1.6 mm from case.

d.  $I_{SD} \leq I_D, \, dI/dt = 100$  A/µs, starting  $T_J = 25 \ ^\circ C.$ 

THERMAL RESISTANCE RATINGS				
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-	62	°C/W
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	-	0.8	0/10



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PARAMETER	SYMBOL	TES	TEST CONDITIONS		TYP.	MAX.	UNIT
Static				•	•		
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, \text{ I}_{D} = 250 \mu\text{A}$		500	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referenc	e to 25 °C, I <sub>D</sub> = 1 mA	-	0.62	-	V/°C
Gate-Source Threshold Voltage (N)	V <sub>GS(th)</sub>	V <sub>DS</sub> =	= V <sub>GS</sub> , I <sub>D</sub> = 250 μΑ	2.0	-	4.0	V
Gate-Source Leakage	I <sub>GSS</sub>	$V_{GS} = \pm 20 V$		-	-	± 100	nA
			V <sub>GS</sub> = ± 30 V	-	-	± 1	μA
		V <sub>DS</sub> =	= 500 V, V <sub>GS</sub> = 0 V	-	-	10	μA
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 400 V	/, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C	-	-	25	
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	$V_{GS} = 10 V$	I <sub>D</sub> = 9.5 A	-	0.192	-	Ω
Forward Transconductance	<b>g</b> fs	V <sub>DS</sub> = 30 V, I <sub>D</sub> =9.5 A		-	3.9	-	S
Dynamic		•		•	•	•	
Input Capacitance	C <sub>iss</sub>		V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 100 V,		1162	-	
Output Capacitance	C <sub>oss</sub>				51	-	pF
Reverse Transfer Capacitance	C <sub>rss</sub>	f = 1 MHz		-	7	-	
Effective Output Capacitance, Energy Related <sup>a</sup>	C <sub>o(er)</sub>	$V_{DS} = 0 V$ to 400 V, $V_{GS} = 0 V$		-	55	-	
Effective Output Capacitance, Time Related <sup>b</sup>	C <sub>o(tr)</sub>			-	164	-	
Total Gate Charge	Qq			-	33	66	
Gate-Source Charge	Q <sub>gs</sub>	V <sub>GS</sub> = 10 V	V <sub>GS</sub> = 10 V I <sub>D</sub> = 9.5 A, V <sub>DS</sub> = 400 V		8	-	nC
Gate-Drain Charge	Q <sub>gd</sub>			-	14	-	1
Turn-On Delay Time	t <sub>d(on)</sub>				15	30	- ns
Rise Time	t <sub>r</sub>	$V_{DD}$ = 400 V, I <sub>D</sub> = 12 A, V <sub>GS</sub> = 10 V, R <sub>a</sub> = 9.1 Ω		-	24	48	
Turn-Off Delay Time	t <sub>d(off)</sub>			-	34	68	
Fall Time	t <sub>f</sub>				18	36	
Gate Input Resistance	Rg	f = 1 MHz, open drain		-	0.85	-	Ω
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET symbol showing the integral reverse p - n junction diode		-	-	14.5	
Pulsed Diode Forward Current	I <sub>SM</sub>			-	-	28	A
Diode Forward Voltage	V <sub>SD</sub>	T <sub>J</sub> = 25 °C, I <sub>S</sub> = 9.5 A, V <sub>GS</sub> = 0 V		-	-	1.2	V
Reverse Recovery Time	t <sub>rr</sub>	$T_{J} = 25 \text{ °C}, I_{F} = I_{S} = 9.5 \text{ A},$ dI/dt = 100 A/ $\mu$ s, V <sub>R</sub> = 25 V		-	265	-	ns
Reverse Recovery Charge	Q <sub>rr</sub>			-	3.2	-	μC
Reverse Recovery Current	I <sub>BBM</sub>			-	23	-	A

Notes

a.  $C_{oss(er)}$  is a fixed capacitance that gives the same energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ . b.  $C_{oss(tr)}$  is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ .

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#### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

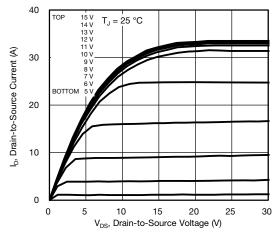


Fig. 1 - Typical Output Characteristics

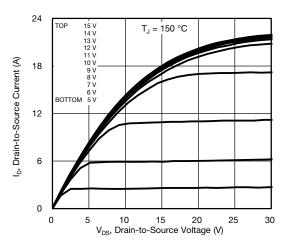


Fig. 2 - Typical Output Characteristics

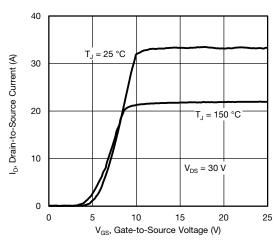


Fig. 3 - Typical Transfer Characteristics

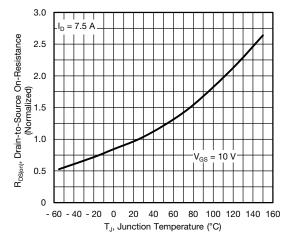


Fig. 4 - Normalized On-Resistance vs. Temperature

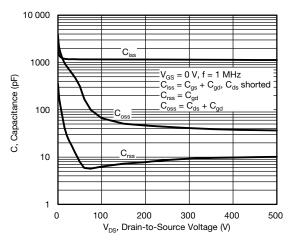


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

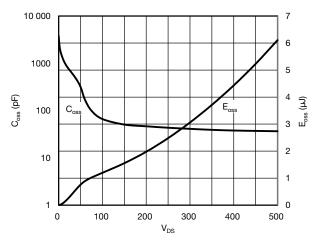


Fig. 6 -  $C_{oss}$  and  $E_{oss}$  vs.  $V_{DS}$ 

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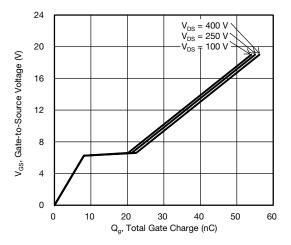


Fig. 7 - Typical Gate Charge vs. Gate-to-Source Voltage

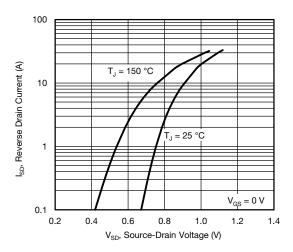
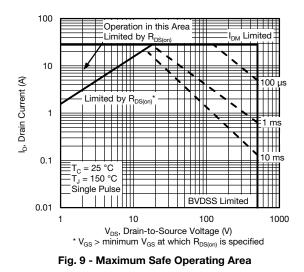


Fig. 8 - Typical Source-Drain Diode Forward Voltage



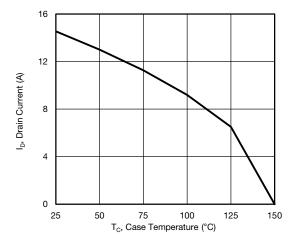


Fig. 10 - Maximum Drain Current vs. Case Temperature

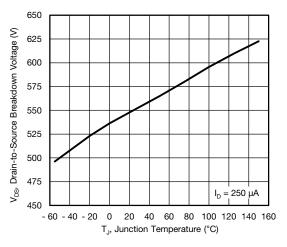
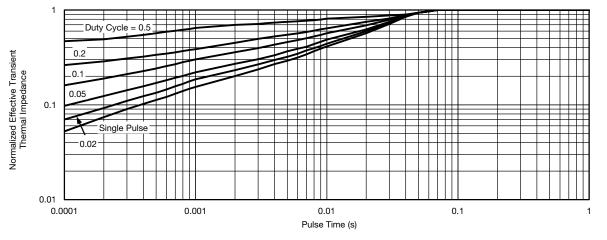


Fig. 11 - Temperature vs. Drain-to-Source Voltage

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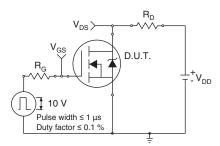


Fig. 13 - Switching Time Test Circuit

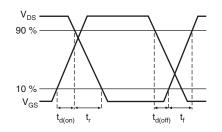


Fig. 14 - Switching Time Waveforms

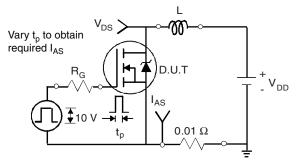


Fig. 15 - Unclamped Inductive Test Circuit

Fig. 16 - Unclamped Inductive Waveforms

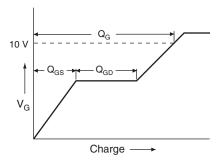
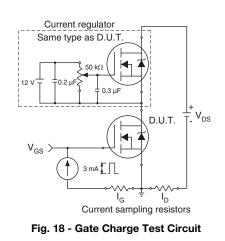


Fig. 17 - Basic Gate Charge Waveform

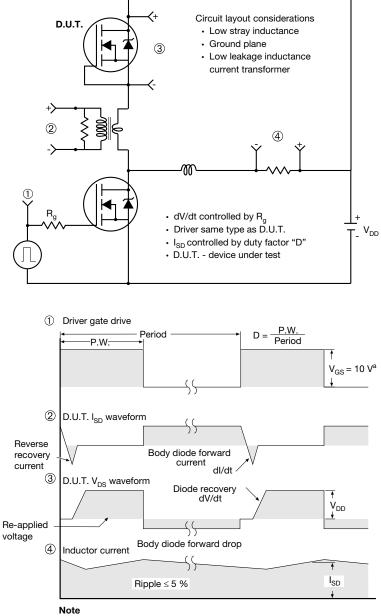


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#### Peak Diode Recovery dV/dt Test Circuit



a.  $V_{GS} = 5 V$  for logic level devices

Fig. 19 - For N-Channel



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